

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/613,598	TAKANO, KENICHI	
		Examiner	Art Unit	Page 1 of 1
		Tianjie Chen	2652	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0047087 A1	03-2004	Fukui et al.	360/324.12
	B	US-2003/0189802 A1	10-2003	Morinaga et al.	360/324.12
	C	US-6,385,017 B1	05-2002	Min et al.	360/324.12
	D	US-US 20040223269A1	11-2004	Wang et al.	360/324.12
	E	US-2004/0141261 A1	07-2004	Hasegawa et al.	360/324.11
	F	US-2003/0202295 A1	10-2003	Wang et al.	360/324.12
	G	US-6,731,478 B2	05-2004	Nakamoto et al.	360/324.1
	H	US-6,633,466 B2	10-2003	Sakaguci et al.	360/327.31
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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